

<b>Notice of References Cited</b>		Application/Control No. 08/840,947	Applicant(s)/Patent Under Reexamination LIU, EDWARD W.	
		Examiner DINH T. LE	Art Unit 2816	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,038,215	08-1991	HADFIELD	358/150
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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